

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/566,604	MORIYA ET AL.
	<b>Examiner</b> Hai H. Huynh	<b>Art Unit</b> 3747

**SEARCHED**

<b>INTERFERENCE SEARCHED</b>			
Class	Subclass	Date	Examiner
above	search	2/5/2007	HHH